



520.41064X00/NT0550US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Akira HAMAMATSU *et al.*

Application No.: 10/050,776

Filed: 18 January 2002

For: APPARATUS AND METHOD FOR INSPECTING DEFECTS

Art Unit: 2877

Examiner: M.P. Stafira

Conf. No: 9567

REQUEST FOR CONSIDERATION OF PREVIOUSLY-SUBMITTED REFERENCES

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-14501

18 July 2005

Sir:

In the matter of the above-identified application, Applicant had previously submitted four (4) foreign references together with the original filing of the application, and the Examiner has yet to acknowledge consideration of such references. For the Examiner's convenience and initialing, provided herewith is a PTO/SB/08A form (replacing the originally-filed non-USPTO-form) for listing such references. For the Examiner's further convenience, also provided herewith is a redundant copy of such four (4) foreign references. Applicant respectfully petitions the Commissioner for an extension for time (to whatever extent necessary), and authorization is herein give to charge any fee deficiency whatsoever to ATSK Deposit Account No. 01-2135.

Respectfully submitted,

Paul J. Skwierawski
Registration No. 32,173
ANTONELLI, TERRY, STOUT & KRAUS, LLP
1300 North Seventeenth Street, Suite 1800
Arlington, Virginia 22209-3873, USA
Telephone 703-312-6600
Facsimile 703-312-6666